

Notice of References Cited			Application/Control No. 10/558,750	Applicant(s)/Patent Under Reexamination JANHUNEN, TOIVO
			Examiner DEMARIS R. WILSON	Art Unit 1791

U.S. PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,364,436	11-1994	Montonen, Jori	65/107
*	B US-2004/0057046	03-2004	Abbott et al.	356/239.1
*	C US-6,980,291	12-2005	Saito, Isao	356/237.2
*	D US-5,726,749	03-1998	Schave, Richard D.	356/239.1
*	E US-2002/0149782	10-2002	Raymond, Christopher J.	356/616
*	F US-7,292,328	11-2007	Kreh et al.	356/237.2
*	G US-7,027,145	04-2006	Segall et al.	356/241.1
*	H US-6,357,263	03-2002	Yajima et al.	65/102
*	I US-5,146,282	09-1992	Guering et al.	356/239.1
*	J US-4,364,766	12-1982	Nitschke, John S.	65/160
*	K US-3,806,330	04-1974		65/158
*	L US-2,766,555	10-1956	JENDRISAK JOSEPH E; et. al.	65/103
*	M US-6,076,373	06-2000	Grodziski, Zenon	65/107

FOREIGN PATENT DOCUMENTS

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
S					
T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	
V	
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X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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